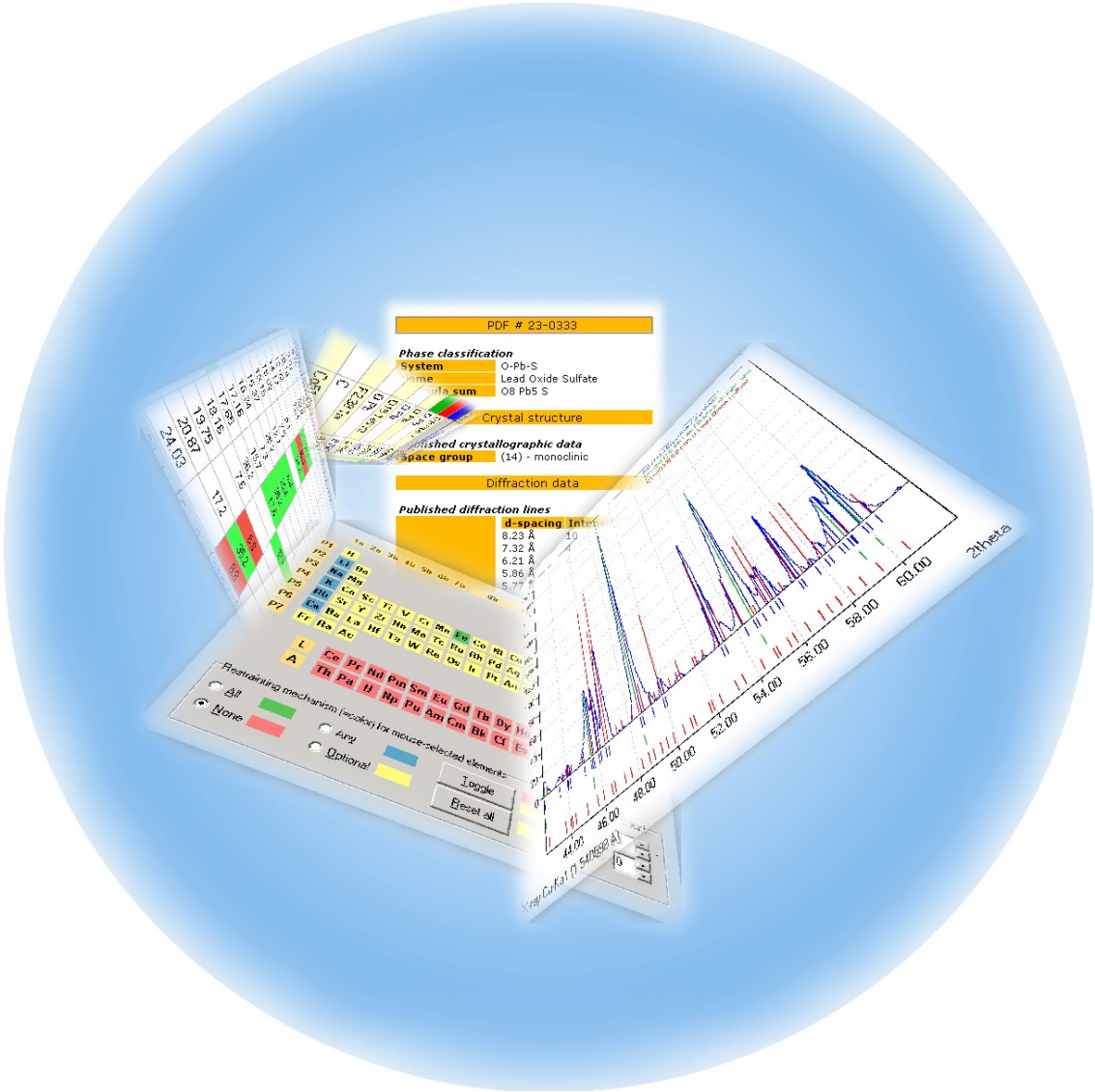
MATCH!

Phase Identification from Powder Diffraction

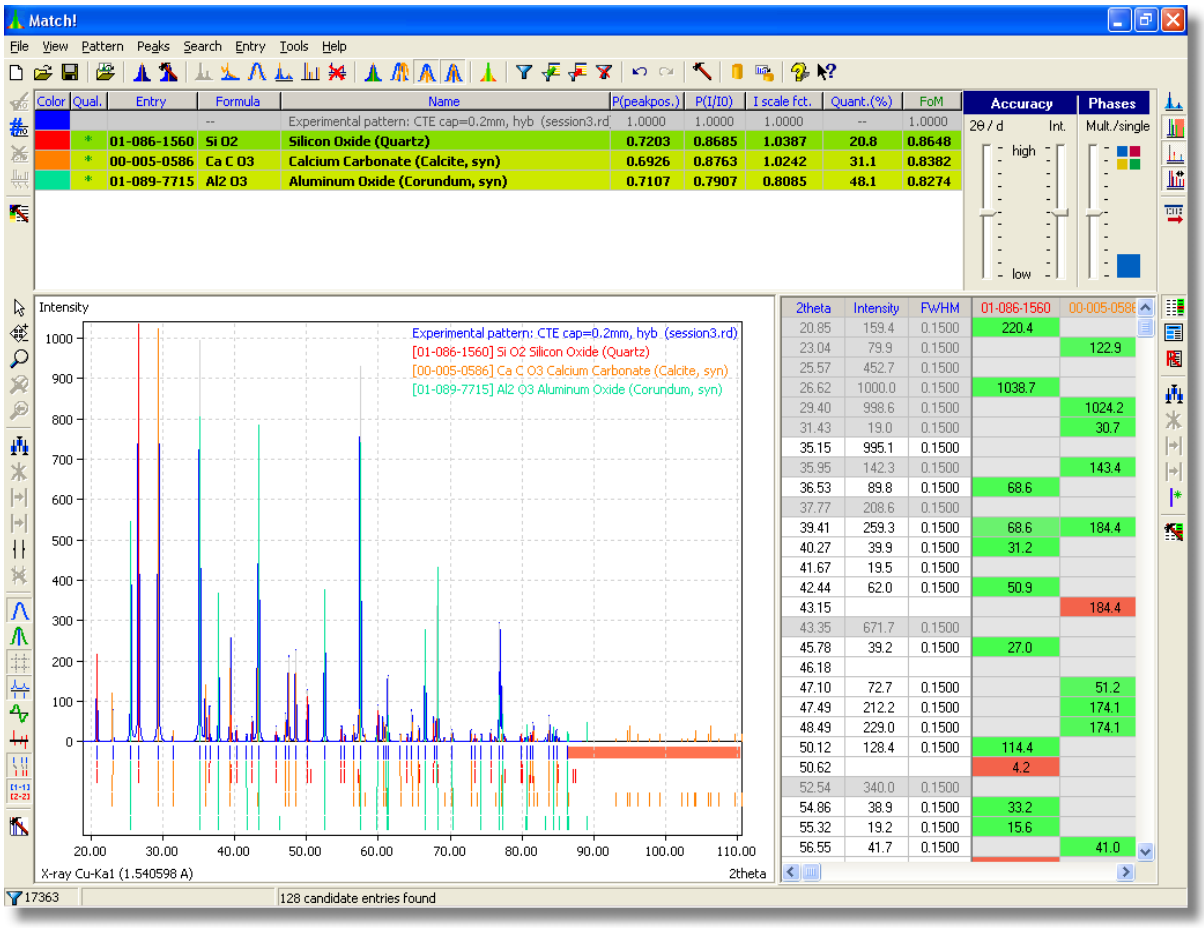


Simply get the most from powder data !

CRYSTAL IMPACT

Match! is an easy-to-use software for phase identification from powder diffraction data, which has become a daily task in material scientists work. Match! compares the powder diffraction pattern of your sample to a database containing reference patterns in order to identify the phases which are present.
Single as well as multiple phases can be identified based on both peak data and raw (profile) data.

As reference database, you can apply any ICDD PDF-2 or PDF-4 product (recommended) and/or create a user database based on your own diffraction patterns. The user database patterns can be edited manually, imported from peak files, or calculated from crystal structure data (e.g. CIF files). It is also possible to add your colleague's user database to your own so that the same data do not have to be entered more than once.



Features

- Fast single and multiple phase identification from powder diffraction data
- Use any ICDD PDF-2 or PDF-4 database and/or your own diffraction data in phase identification
- Comfortable user database manager for easy maintenance of user data (add/import/edit/delete/sort entries)
- Fully integrated handling of your own diffraction data with PDF data (search-match, retrieval, data viewing)
- Automatic residual searching with respect to identified phases
- Automatic raw data processing including peak searching, profile fitting and 2theta error correction
- Comfortable manual editing of peaks (add/shift/delete/fit to exp. profile)
- Semi-quantitative analysis (Reference Intensity Ratio method)
- Straight-forward usage of additional knowledge (composition, crystallographic data, color, density etc.)
- Multiple step undo/redo
- Full parameter control with instant Results List rearrangement
- Intensity contribution to figure-of-merit can be reduced for preferred-orientation cases
- Online update option (automatic or manual)

System Requirements

- ICDD PDF-2 or PDF-4 database (recommended) and/or own diffraction patterns as reference
- Microsoft Windows 98, ME, NT4, 2000 or XP
- Microsoft Internet Explorer 5.01 (or higher)
- 64 MB of RAM (128 MB recommended)
- 600 MB of free disc space
- **Supported diffraction data file formats**: Stoe (*.raw, *.pks), Philips/PANalytical (*.rd, *.udf, *.udi), Bruker/Siemens (*.raw, *.dif), Rigaku (*.raw), Siemens (*.uxd), DBWS (*.rfl, .dat), SCINTAG (*.raw, *.rd), Jade/ MDI/SCINTAG (*.mdi), Inel (*.dat), ASCII profile (start, step, int. or 2 columns), ENDEAVOUR peak list (2 columns: 2theta/d int.; *.dif)

Prices*

	non-profit org.	profit org.
Single licence	399 €	798 €
Site licence**	798 €	1,596 €
Campus licence***	1,596 €	3,192 €

* Prices do not include taxes which may be due.
** Unlimited number of installations within one institute/dept.
*** Unlimited number of installations within one university/company.

CRYSTAL IMPACT

CRYSTAL IMPACT GbR
Postfach 12 51
D-53002 Bonn
Germany

Tel: +49 (228) 981 36 43
Fax: +49 (228) 981 36 44
E-mail: info@crystalimpact.com
http://www.crystalimpact.com